

Test Report

No.: EKR22700636

Date: 18-Jul-2022

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NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS


The following sample(s) was/were submitted and identified by the applicant as:


Sample Submitted By : NXP SEMICONDUCTORS
Sample Name : CHANDLER BUMPED WAFER

Sample Receiving Date : 11-Jul-2022
Testing Period : 11-Jul-2022 to 18-Jul-2022

Test Requested : (1) As specified by client, with reference to RoHS 2011/65/EU Annex II and amending Directive (EU) 2015/863 to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP contents in the submitted sample(s).
(2) Please refer to next pages for the other item(s).

Test Results : Please refer to following pages.


Ray Chang, Ph.D./Department Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory-Kaohsiung



PIN CODE: 2758614A

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Test Part Description

No.1 : WAFER

Test Result(s)

Test Item(s)	Method	Unit	MDL	Result
				No.1
Cadmium (Cd) (CAS No.: 7440-43-9)	With reference to IEC 62321-5: 2013, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Lead (Pb) (CAS No.: 7439-92-1)		mg/kg	2	58000
Mercury (Hg) (CAS No.: 7439-97-6)	With reference to IEC 62321-4: 2013+ AMD1: 2017, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Hexavalent Chromium Cr(VI) (CAS No.: 18540-29-9)	With reference to IEC 62321-7-2: 2017, analysis was performed by UV-VIS.	mg/kg	8	n.d.
Monobromobiphenyl	With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.	mg/kg	5	n.d.
Dibromobiphenyl		mg/kg	5	n.d.
Tribromobiphenyl		mg/kg	5	n.d.
Tetrabromobiphenyl		mg/kg	5	n.d.
Pentabromobiphenyl		mg/kg	5	n.d.
Hexabromobiphenyl		mg/kg	5	n.d.
Heptabromobiphenyl		mg/kg	5	n.d.
Octabromobiphenyl		mg/kg	5	n.d.
Nonabromobiphenyl		mg/kg	5	n.d.
Decabromobiphenyl		mg/kg	5	n.d.
Sum of PBBs		mg/kg	-	n.d.
Monobromodiphenyl ether		mg/kg	5	n.d.
Dibromodiphenyl ether		mg/kg	5	n.d.
Tribromodiphenyl ether		mg/kg	5	n.d.
Tetrabromodiphenyl ether		mg/kg	5	n.d.
Pentabromodiphenyl ether		mg/kg	5	n.d.
Hexabromodiphenyl ether		mg/kg	5	n.d.
Heptabromodiphenyl ether		mg/kg	5	n.d.
Octabromodiphenyl ether		mg/kg	5	n.d.
Nonabromodiphenyl ether		mg/kg	5	n.d.
Decabromodiphenyl ether	mg/kg	5	n.d.	
Sum of PBDEs	mg/kg	-	n.d.	

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Test Item(s)	Method	Unit	MDL	Result
				No.1
Butyl benzyl phthalate (BBP) (CAS No.: 85-68-7)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Dibutyl phthalate (DBP) (CAS No.: 84-74-2)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Diisobutyl phthalate (DIBP) (CAS No.: 84-69-5)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Di-(2-ethylhexyl) phthalate (DEHP) (CAS No.: 117-81-7)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Diisononyl phthalate (DINP) (CAS No.: 28553-12-0, 68515-48-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Diisodecyl phthalate (DIDP) (CAS No.: 26761-40-0, 68515-49-1)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Di-n-octyl phthalate (DNOP) (CAS No.: 117-84-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Di-n-pentyl phthalate (DNPP) (CAS No.: 131-18-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Antimony (Sb) (CAS No.: 7440-36-0)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Beryllium (Be) (CAS No.: 7440-41-7)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Arsenic (As) (CAS No.: 7440-38-2)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Fluorine (F) (CAS No.: 14762-94-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.
Chlorine (Cl) (CAS No.: 22537-15-1)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.
Bromine (Br) (CAS No.: 10097-32-2)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.
Iodine (I) (CAS No.: 14362-44-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.

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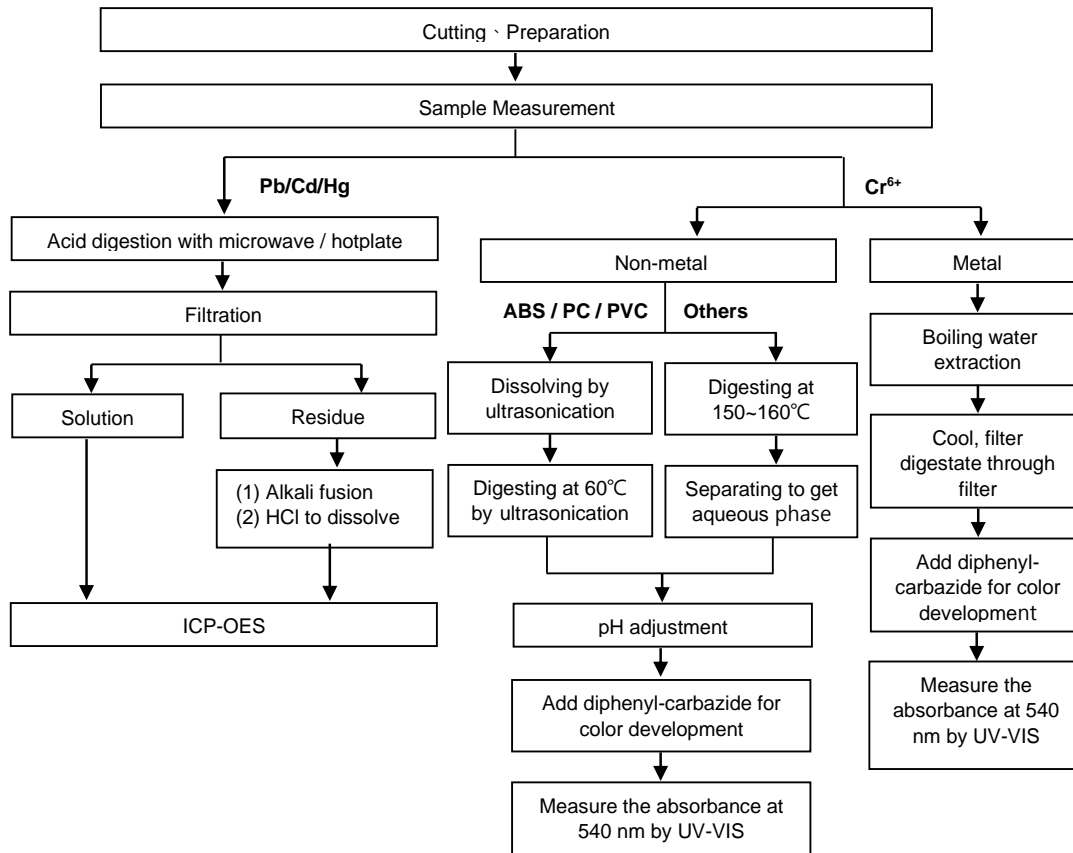
Note :

1. mg/kg = ppm ; 0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit
3. n.d. = Not Detected (Less than MDL)
4. "-" = Not Regulated

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Analytical flow chart of Heavy Metal

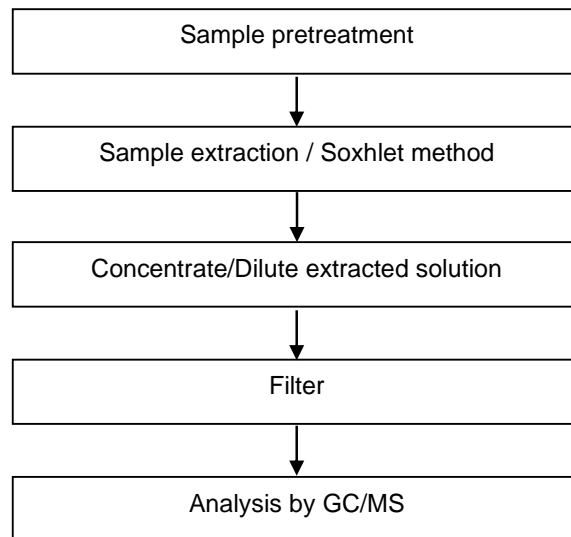
These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)



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PBB/PBDE analytical FLOW CHART

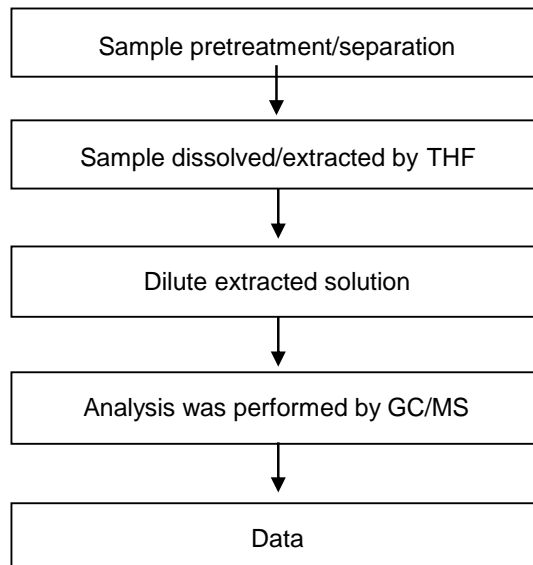


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Analytical flow chart of phthalate content

【Test method: IEC 62321-8】

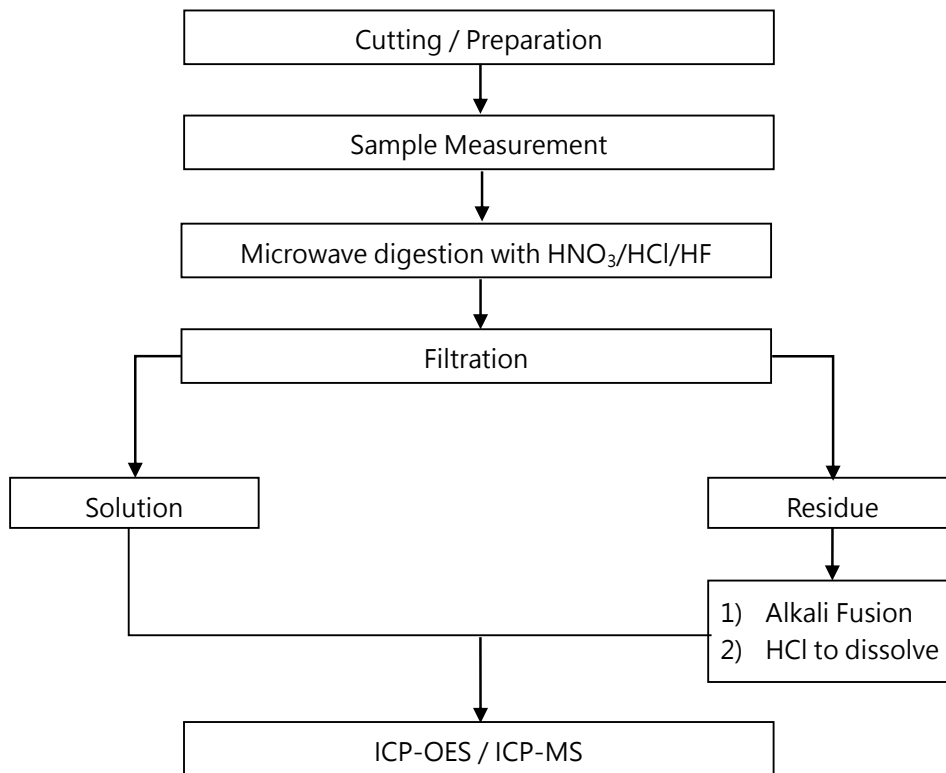


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Analytical flow chart of Elements (Heavy metal included)

These samples were dissolved totally by pre-conditioning method according to below flow chart.

【Reference method : US EPA 3051 · US EPA 3052】

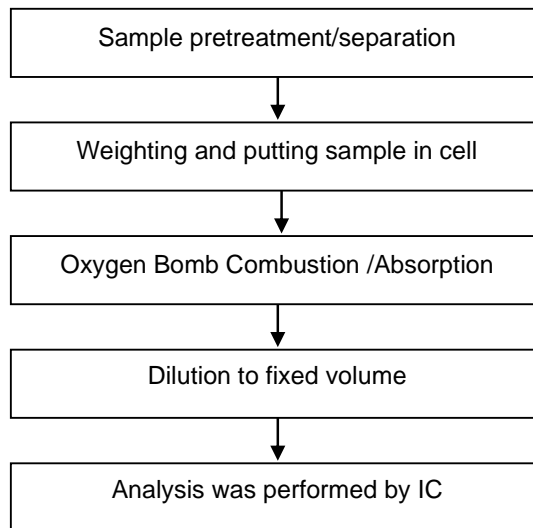


* US EPA 3051 method does not add HF.

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Analytical flow chart of Halogen

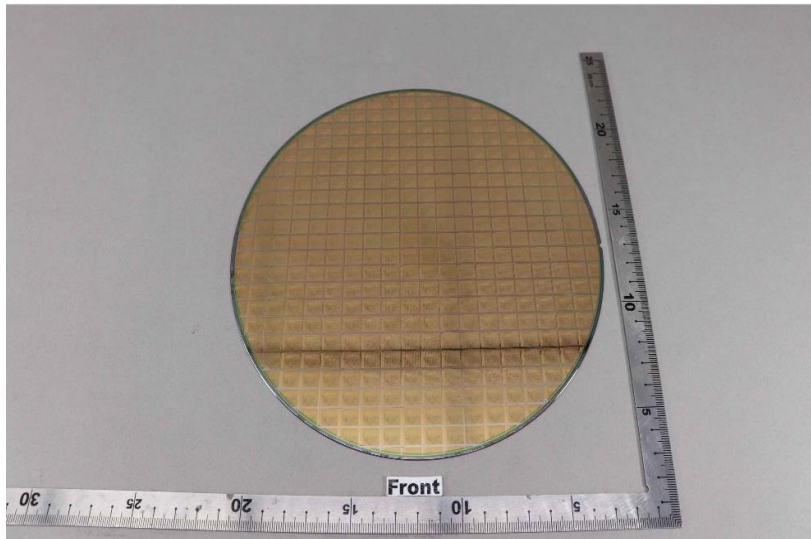


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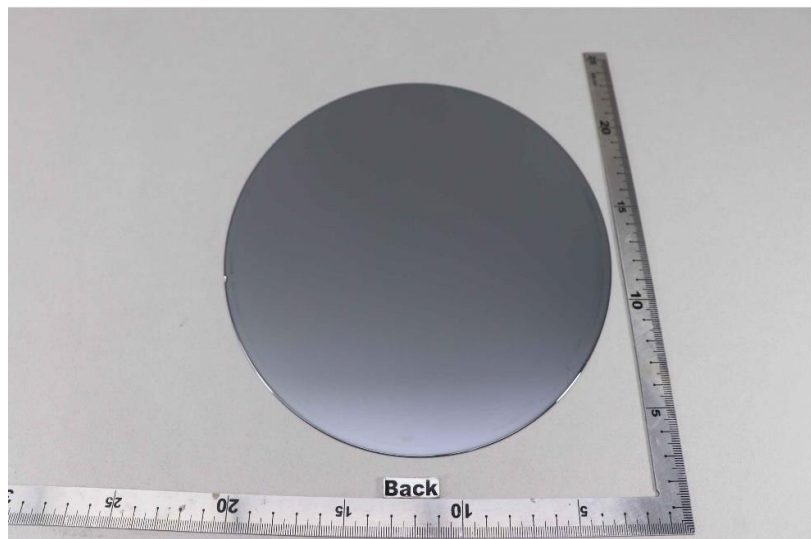
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* The tested sample / part is marked by an arrow if it's shown on the photo. *

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** End of Report **

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